Atomic-scale Considerations on LaNiO₃-La₂CuO₄ Heterostructures: Interface thermoelectricity Relationship

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It is well-known that the electrical transport along interfaces [1] and boundaries [2] can be modified by several orders of magnitudes, and various examples such as LaAlO₃/SrTiO₃ [3] and La₂CuO₄-based interfaces [4], were extensively studied. Moreover oxygen stoichiometry and exchange dynamics [5] play an important role as well. Hence, the utilization of interface engineering and linking it with defect chemistry can be a powerful tool to tailor the electrical transport properties of oxides.

In this study, by means of the atomic-layer-by-layer oxide molecular beam epitaxy technique, we designed oxide heterostructures consisting of tetragonal K₂NiF₄-type La₂CuO₄ (LCO) and perovskite-type LaNiO₃ (LNO) layers with different thicknesses to assess the heterostructure–thermoelectric property–relationship. The temperature dependence of the Seebeck coefficient S(T) and the electrical conductivity $\sigma(T)$ were measured simultaneously under 1 bar oxygen between 300 K and 800 K, using ULVAC ZEM3 system. For the investigations, a JEOL JEM-ARM200F STEM equipped with a cold field-emission electron source, a probe Cs-corrector (DCOR, CEOS GmbH), a large solid-angle JEOL Centurio SDD-type energy-dispersive X-ray spectroscopy (EDXS) detector, and a Gatan GIF Quantum ERS spectrometer was used.

We observed the dependency of transport properties on the individual layer thickness, interface intermixing, and oxygen exchange dynamics in LCO layers that occurs at high temperatures. In particular, as the thickness of the individual layers was reduced, the $\sigma(T)$ decreased and the sign of the S(T) changed (Figure 1), revealing the contribution of the individual layers, where the possible interfacial contributions cannot be ruled out. High-resolution scanning transmission electron microscopy (HR-STEM) investigations showed that a substitutional solid solution of La₂(CuNi)O₄ was formed, when the thickness of the constituent layers was decreased. Moreover, in such LNO-LCO heterostructures with relatively thick LNO and LCO layers (8 u.c. and 6 u.c. thick) the thermoelectric properties are determined by the more conducting LNO layers and can be described by the parallel slab model [6, 7].



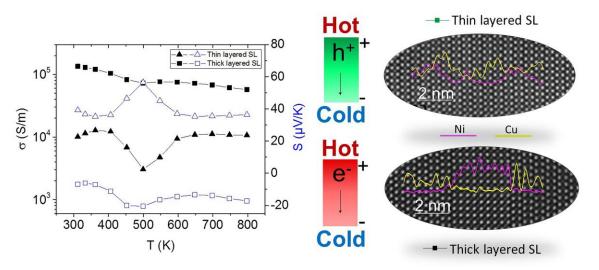


Figure 1. Seebeck coefficient S(T) and electrical conductivity $\sigma(T)$ of thin & thick layered superlattices (SLs) and HR-STEM images with Cu & Ni elemental profiles[5]

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[7] This project has received funding from the European Union's Horizon 2020 research and innovation programme under grant agreement No. 823717 – ESTEEM3.